

Mühlbauer Group Introduction





Muhlbauer, Inc.

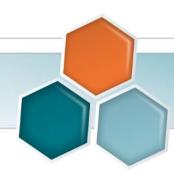




MUHLBAUER, INC. 226 Pickett's Line Newport News, VA 23603-1366 U.S.A.

Tel.: +757-947-2820 Fax: +757-947-2930

E-mail: info@muhlbauer.com Web: www.muhlbauer.com





A SOLUTION is more than just a machine



Process

Flexible
High speed
Low COO

100% Vision
QUALITY
INSPECTION

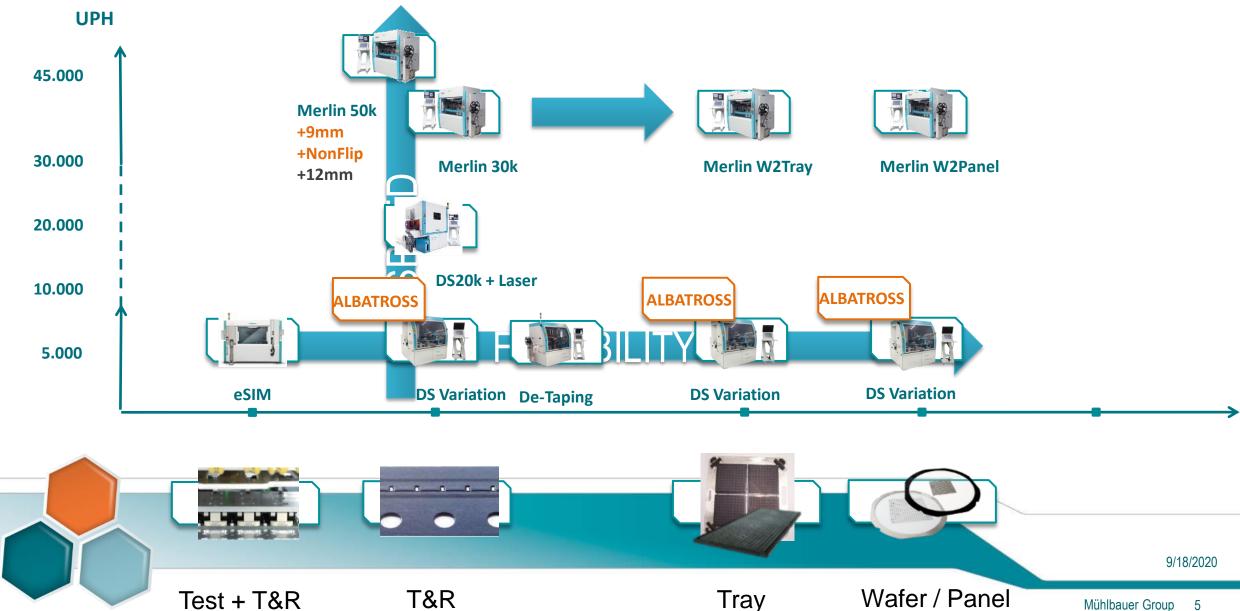
Life cycle Management

> FACTORY Smartification



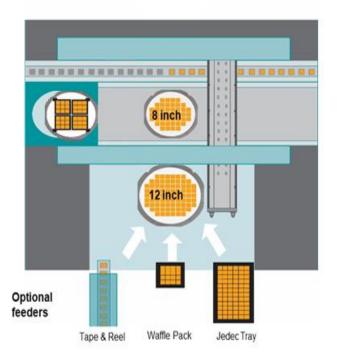
Process overview Pick & Place Technology





DS Variation Applications ecoLINE





Reconstructed wafer Indexer for up to 12" wafers



 Optional Waffle Packs / JEDEC Trays or Hoop Ring can be mounted onto adapter plate at input or output:

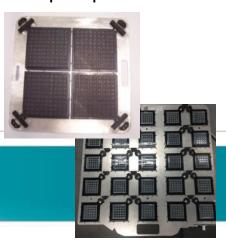


Pick from Waffle pack mounted on adapter plate

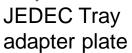


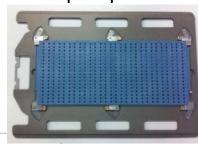


Waffle Pack adapter plates









ALBATROSS: DOUBLE AS FLEXIBLE, BIG DIE READY





DOUBLE AS FLEXIBLE

- Wafer / Hoop ring
- JEDEC Tray, T&R / DeTaping
- 12" Wafer / 0,3 35 / 45mm Die



Benefits: Bin Sorting

- MULTI OUTPUT STATION:
- 6* Tape & Reel
- 2* JEDEC Tray
- 12* Waffle pack
- Reconstructed Panel /5µm placement acc.
- Automatic Tool Changer



Merlin: high-speed DIE SORTER 2020





Smart Quality Sorter

- HIGH VOLUME MANUFACTURING → 450k / 650k a day
- Smart Intelligence = super fast product change over
- 12" Wafer / 0,2 7 or 9mm Die

Quality, Speed & Automation

- 100% Quality with 6 Side Inspection
 - 15pic per die = 180pic per second
- Tape and Reel
- **Reconstructed Wafer and Tray**
- **ONLINE IR INSPECTION, Sidewall and Backsite**
- **ARC AUTOMATION**

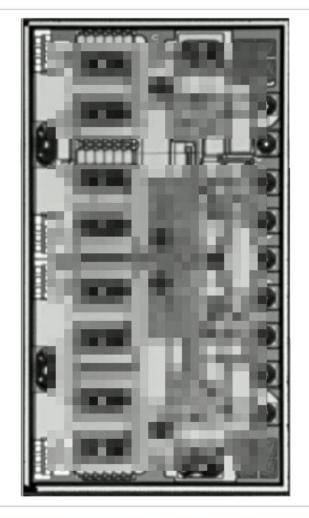


Let's talk about Inspection



Who can see the crack?

Die surface with standard coaxial light (pixelated to hide confidential details)





Backside (visible light)

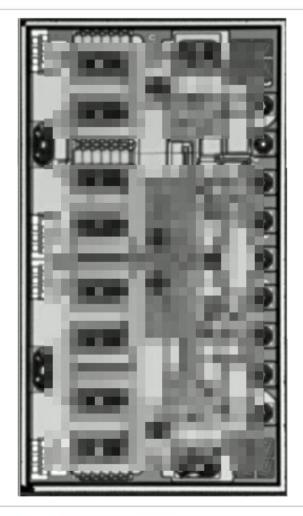


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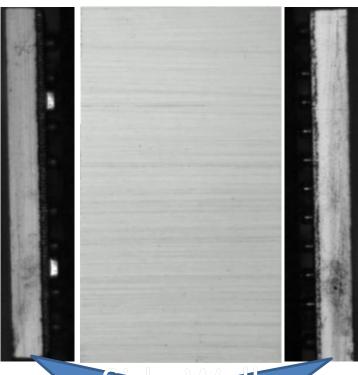
Let's talk about Inspection



Adding side wall inspection

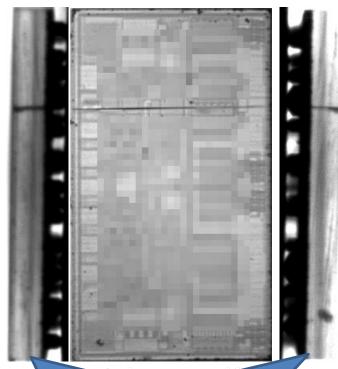
=> Only with IR light cracks can be seen well enough for reliable detection

Inspection with visible light



Side wall

Inspection with IR light

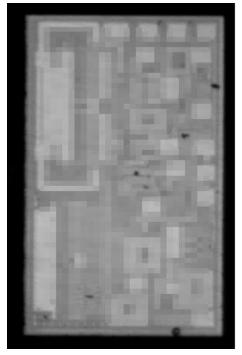


Side wall

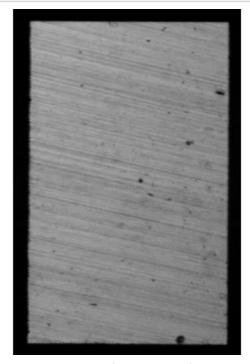


Artificial Intelligence / IR BSI with reduction of over-rejects

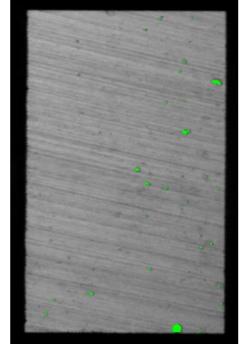




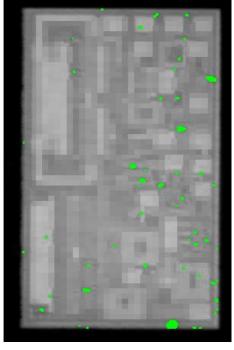
IR BSI with particles



Vis BSI with particles



Particles detected, acceptable on back side With filter:



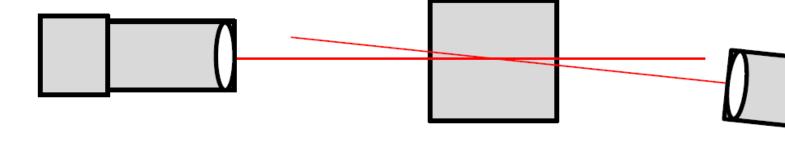
Detected particles as areas to ignore in IR picture <3% reject, as particles on back side are ignored

Without particles filter: 30% reject due to particles



New: angle IR Sidewall





Contrast and size of crack depend on its direction.

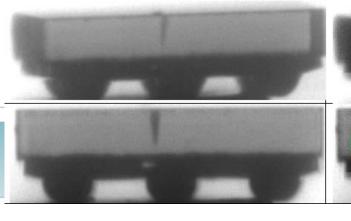
View with angle

Straight view

Sometimes straight view gives better detectability, sometimes the angled view.

View with angle

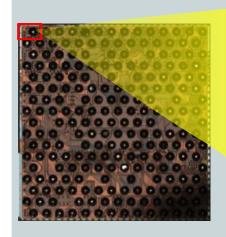
Straight view



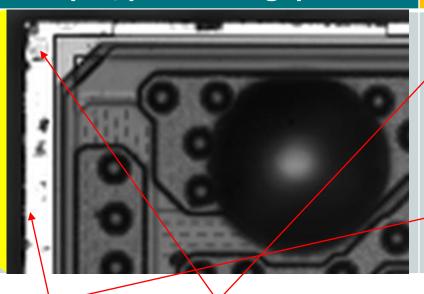
Using both gives the best reliability



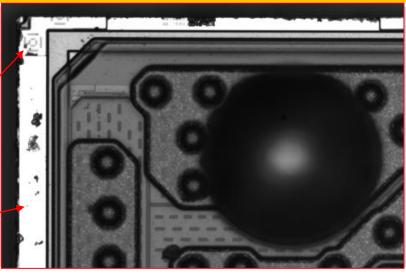
Resolution



3μm/pix – 4 Megapixel



1μm/pix – 25Megapixel



Impossible to detect small defects or check control pattern



Higher resolution at -> full speed <- for -> all a



TRACEABILITY of Products, Quality and Machine Status

- Real time data => OPC/UA
- Machine performance & Product quality
- Statistic, Monitor, Reporting
- Break down Analysis
- Factory/Output Improvement

PalaMax /BIG Data Bridge

PalaMax §

Material handling

Smart Material Management

- Automatic Material Management (Wafer / Reels) by AIV / OHV
- Operator assisted product change over

Factory martificati

Smart Product change over

- Smart Product Change over, RMS
- Predictive Maintenance

n





MATERIAL MANAGEMENT

Consideration of Production Materials:

- Wafer in a Cassette (input)
- Can Automatically be Loaded with
 - AIV (Automatic Intelligent Vehicle)
 - or TOP LOADER via
 - Load Port solution









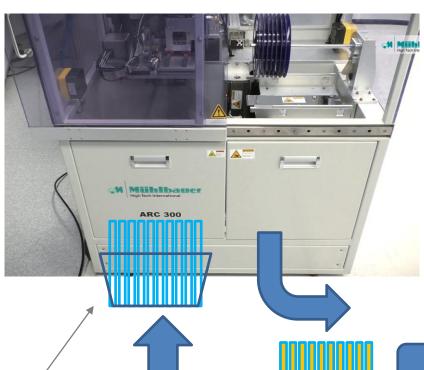


MATERIAL MANAGEMENT: OUTPUT REEL CONCEPT

- Software connection between die sorter and fleet manager via PalaMax
- AIV pick drawer box from warehouse
- Bring to die sorter by AIV
- Arrive and communicate with die sorter
- Change the empty cassette to a new cassette with new wafers automatically



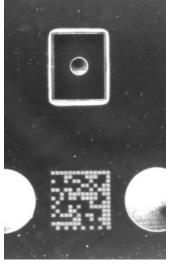
Reel size input/output







- Remote machine operation
- Save 50% TECHs on floor



MACHINE TRACEABILITY IN REAL TIME

- Detailed reporting tools
- Drill-down data analysis
- Identify error reasons and their root causes
- Improve production behavior
- Smart Factory / AIV communication

PRODUCT TRACEABILITY

- Drill-down analysis
- Get the VALUE of Vision inspection
- Identify reject reasons and their root causes











Challenges and New Developments in Die Sorting

MUHLBAUER, INC.

Gerald Steinwasser 226 Pickett's Line

Newport News, VA 23603-1366

U.S.A.

Tel.: +757-947-2820

Fax: +757-947-2930

E-mail: gerald.steinwasser@muhlbauer.com

Web: www.muhlbauer.com



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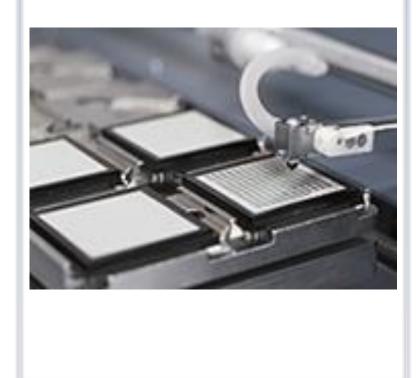
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Tel.: +757-947-2820 Fax: +757-947-2930

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